Appl. No. 09/857,960

Amdt. dated January 5, 2005

Reply to Office Action of September 8, 2004

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of the Claims:

Claims 1-31 (Canceled)

Claim 32 (Currently amended)

A method for the differentiated examination of various structures in a biological preparation

using a microscope, said method comprising the steps of:

A) assigning particles with a specific diameter and specific characteristics to said

structures;

B) detecting said structures by detecting said particles specifically bound in or on said

structures of said preparation using a light that acts on said particles, said particles

possessing constant characteristics independent of the time of irradiation by said light;

C) simultaneously recording an a microscopic image of said detected particles and at least

one microscopic image of said structures using the microscope; and,

D) evaluating said recorded images using digital image processing.

Claim 33 (Previously presented)

The method as recited in Claim 32, wherein said particles are detected by selecting a

wavelength of suitable light being as a function of said diameter and of said specific

characteristics of the particles such that said particles are detected on the basis of a Mie

scatter occurring on said particles.

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Claim 34 (Previously presented)

The method as recited in Claim 32, wherein said particles are detected by selecting a

wavelength of a suitable light as a function of said diameter and of said specific

characteristics of said particles such that said particles are detected on the basis of a plasmon

signal occurring on said particles.

Claim 35 (Previously presented)

The method as recited in Claim 33, wherein said wavelength of said light is larger than, or is

approximately equal to, said diameter of said particles.

Claim 36 (Cancelled)

Claim 37 (Previously presented)

The method as recited in Claim 32, wherein said particles are metallic particles or particles

metalized on the surface.

Claim 38 (Previously presented)

The method as recited in Claim 37, wherein said particles are formed as ellipsoids or beads.

Claim 39 (Previously presented)

The method as recited in Claim 33, wherein said particles are detected through the Mie-

reflexes occurring there in transmission microscope mode.

Claim 40 (Previously presented)

The method as recited in Claim 39, wherein said microscope is a conventional polarization

transmission microscope or a confocal polarization transmission microscope.

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Claim 41 (Previously presented)

The method as recited in Claim 33, wherein the specific detection of the particles is achieved

via the Mie-reflexes occurring there in the reflection microscope mode.

Claim 42 (Previously presented)

The method as recited in Claim 41, wherein said microscope is a conventional polarization

reflection microscope or a confocal polarization reflection microscope.

Claim 43 (Previously presented)

The method as recited in Claim 32, wherein said light is produced using a high-pressure lamp

as a light source.

Claim 44 (Previously presented)

The method as recited in claim 43, wherein said light source comprises means for

wavelength selection and polarization.

Claim 45 (Previously presented)

The method as recited in Claim 32, wherein said light is produced using a laser as a light

source, said laser emitting polarized light of one wavelength.

Claim 46 (Previously presented)

The method as recited in Claim 32, wherein said light is produced using an optical parametric

oscillator as a light source, the wavelength of said light being variable using said optical

parametric oscillator, whereby a maximum Mie-signal for a specific particle type can be

measured.

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Claim 47 (Previously presented)

The method as recited in Claim 32, wherein said light is produced using a laser as a light

source, said laser emitting polarized light of several different wavelengths, and means for

selecting wavelengths is connected in series to said laser.

Claim 48 (Previously presented)

The method as recited in Claim 47, wherein said means for selecting wavelengths is

integrally connected in to said laser.

Claims 49-53 (Canceled)

Claim 54 (Previously presented)

The method as recited in Claim 32, wherein said particles are coated on the surface and the

coating enables a specific bonding to corresponding complementary structures of said

preparation.

Claim 55 (Currently amended)

The method as recited in Claim 32, wherein said at least one microscopic image images

eomprises comprise a conventional transmitted light microscopic image images.

Claim 56 (Currently amended)

The method as recited in Claim 32, wherein said at least one microscopic image images

comprises comprise a conventional reflected light microscopic image images.

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Claim 57 (Currently amended)

The method as recited in Claim 32, wherein said at least one microscopic image images

comprises comprise a conventional transmitted light microscopic image and a conventional

reflected light microscopic image.

Claim 58 (Currently amended)

The method as recited in Claim 32, wherein said at least one microscopic image images

comprises comprise a plurality of conventional transmitted light microscope images and

conventional reflected light microscope images, wherein said conventional transmitted light

microscope images and eonventional reflected light microscope images are obtained under a

plurality of lighting and detection angles.

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